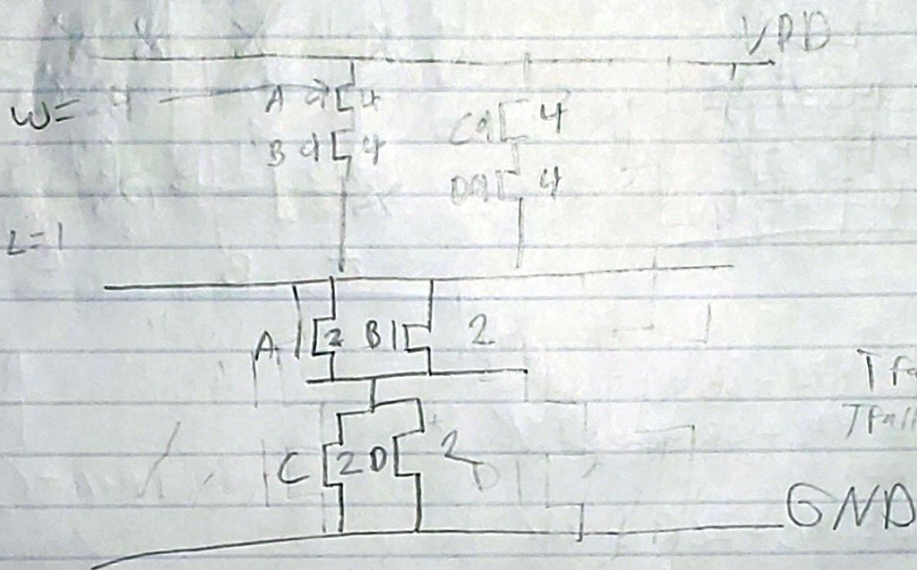


Brian Landy Digital IC design HW4

- 1) Rising and falling propagation delay of worst case gate that implements $(A+B)(C+D)$ i.e.
Do with RC delay + E/more delay



$$T_{fall} = R_{eq} C_{eq}$$

$$T_{fall} = \frac{R_1 R_2}{R_1 + R_2} C_{eq}$$

$$5RC + 10RC$$

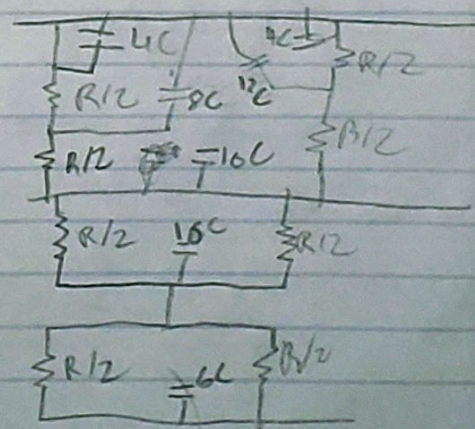
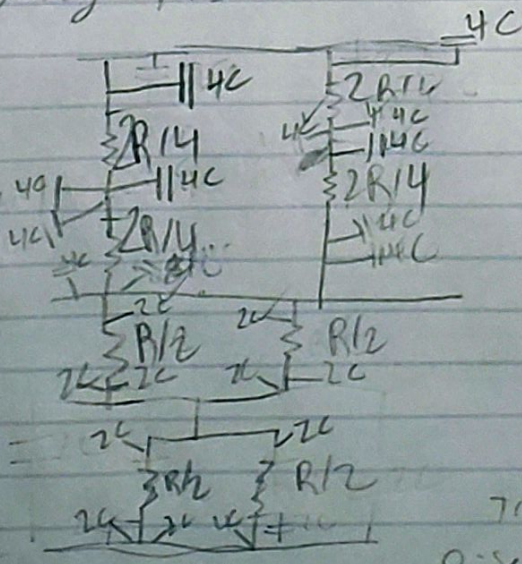
$(A+B)(C+D) \rightarrow 1$ $(A+B)(C+D) \rightarrow 0$

$\rightarrow (A+B)(C+D)$ $\rightarrow ACD$

R+C delay rise + fall

Electrically isolated from VDD

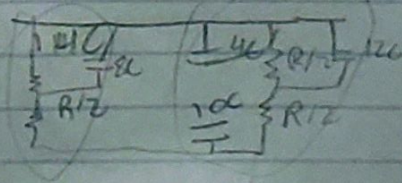
Worst case
Rise:
 $16RC$
Worst case,
fall: $15RC$



Rise

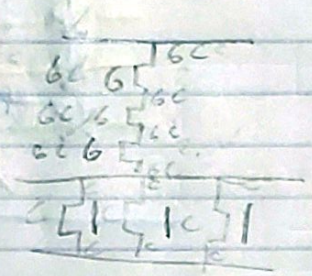
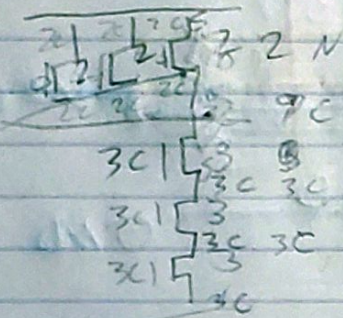
$T_{rise} \text{ case 1} \rightarrow R/2 \cdot 8C + R \cdot 10C = 14RC$

$T_{rise} \text{ case 2} \rightarrow R/2 \cdot 12C + R \cdot 10C = 16RC$

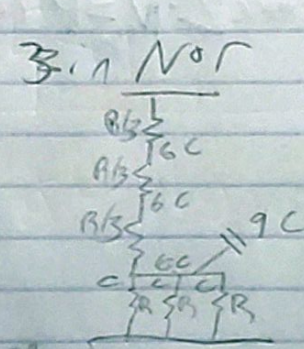
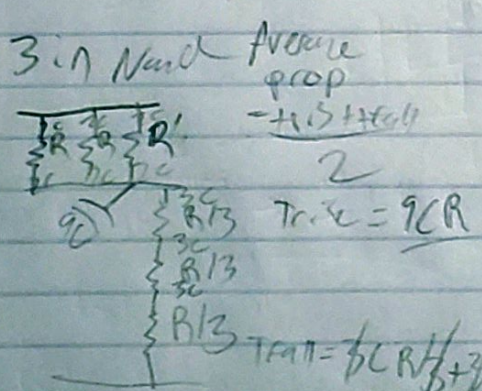


$\frac{S}{L_0}$ $\frac{L_1}{L_0}$

2) which has worse parasitic capacitance N-in NAND or N-in NOR?
Evaluate delays and compare. Assume diff. capacitance for N-input NAND. N-input NOR



Diffusion sharing happens when S + d touches



$N=3$

$$T_{rise} = \frac{R}{3} C_C + \frac{2R}{3} C_L + R C_C$$

$$= 2RC + 4RC + 6RC$$

$$= 12RC$$

$$T_{pd} = \frac{(9+6)RC}{2} = 7.5RC$$

NAND

$$T_{pd} = \frac{9CR + 12RC}{2} = \frac{21RC}{2}$$

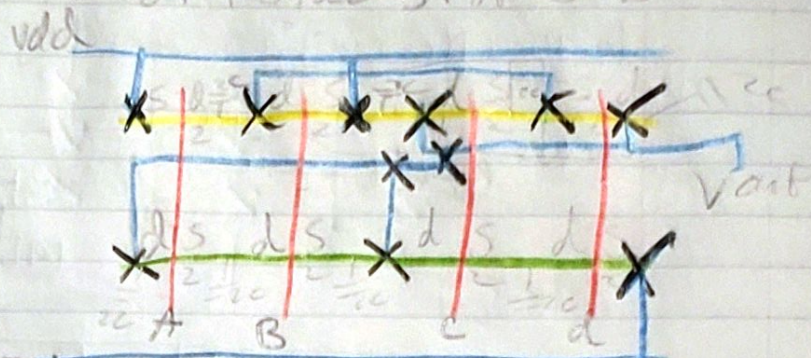
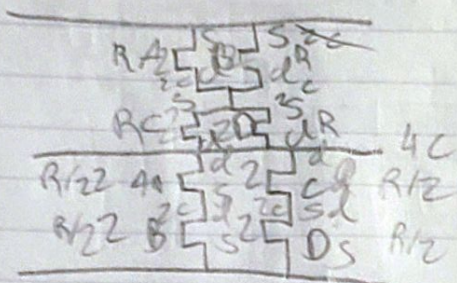
NOR

Worse N-input parasitic delays come from NOR

Metal
Poly

P
N

3) Draw stick diagram of $(AB+CD)$ size $(4R \times 8C)$
 Rise + Fall are same as inverter. Every large width, assume diffusion is same as inverter. dirFS has \rightarrow Flip S+D



$$T_{rise1} = R4C + 2R4C = 12RC$$

$$T_{fall2} = R4C + 2R4C = 12RC$$

$$T_{fall11} = 4CR/2 + 2CR = 4RC$$

$$T_{fall12} = 4CR/2 + 2CR = 4RC$$

$$R = 12RC$$

$$F = 4RC$$

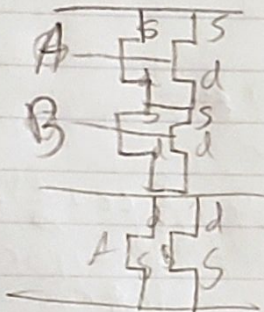
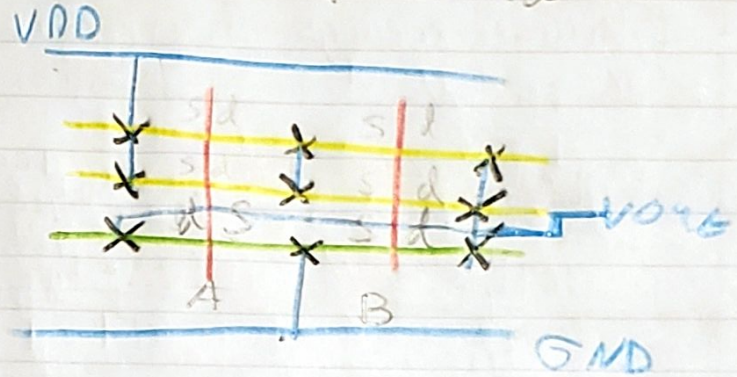
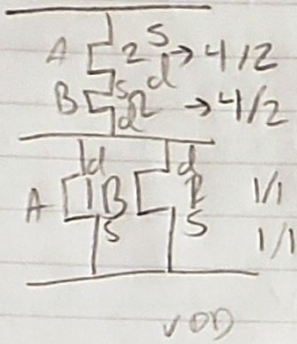
$$T_{prop} = \frac{(R+F)}{2}$$

$$2$$

$$T_{prop} = 8RC$$

$$\overline{(A+B)}$$

4) Stick diagram 2 input NOR, PW-2-NW



✓ folded
CMT type
one 2-N_{in}=P_{in}